

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
12406-148US1Application No.
10/567,935**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant
Johannes Baur et al.Filing Date
February 9, 2006

Group Art Unit

37 CFR §1.98(b)

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/SC/	AA	5,792,698	8/11/1998	Nishitani			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
/SC/	AH	JP 07-162037	6/23/1995	Japan	H01L	33/00	See U.S. 5,792,698	
	AI							
	AJ							
	AK							
	AL							

Other Documents (Include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
/SC/	AM	Copy of European Search Report dated 06/01/2006 for application no. 04 762 694.0 - 1235
	AN	
	AO	
	AP	

Examiner Signature

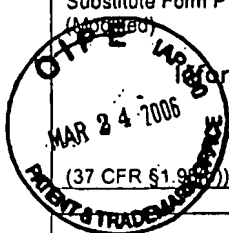
/Sara Crane/

Date Considered

06/24/2007

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Revised)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12406-148US1	Application No. 10/567,935
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Johannes Baur et al.	
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**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/SC/	AA	5,310,623	05/10/1994	Gal			
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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
/SC/	AE	101 35 190	02/06/2003	Germany	H01L	33/00	Abstract Only	
	AF	1 271 665	01/02/2003	EPO	H01L	33/00		
	AG	1 324 399	07/02/2003	EPO	H01L	33/00		
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Examiner Initial	Desig. ID	Document
/SC/	AK	G.A. Neuman, "Anti-reflective coatings by APCVD using graded index layers", <u>Journal of Non-Crystalline Solids</u> , Vol. 218, pp. 92-99 (1997)
	AL	H.J. Quenzer et al., "Anodic-Bonding on Glass Layers Prepared by Spin-on Glass Process: Preparation Process and Experimental Results", <u>Proceedings of Transducers 01/Eurosensors XV</u> , (June 10-14, 2001)
	AM	I. Schnitzer et al., "30% external quantum efficiency from surface textured, thin-film light-emitting diodes", <u>Applied Physics Letter</u> , Vol. 63, No. 16, pp. 2174-2176 (October 18, 1993)
	AN	S. Warnck "RELIEF - Mass production of low-cost products with microrelief surfaces by means of CD injection molding", <u>Information Series of VDI-VDE-Technologiezentrum Informationstechnik GmbH</u> , (German Federal Ministry for Education and Research) No. 36-2002 (German and English translation)
	AO	R. Windisch et al., "Impact of texture-enhanced transmission on high-efficiency surface-textured light-emitting diodes", <u>Applied Physics Letters</u> , Vol. 79, No. 15, pp. 2315-2317 (October 8, 2001)
/SC/	AP	<u>Reducing Reflection by means of Submicron Structures in ORMOCER Layers</u> , Fraunhofer Institute Silicate Research, http://www.isc.fraunhofer.de/gb/ormocere/o3_7.html
	AQ	

considered
but no
date
provided
no date

Examiner Signature /Sara Crane/	Date Considered 06/24/2007
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